
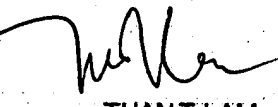


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/765,311	WENDELL ET AL.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION											
ORIGINAL				CROSS REFERENCE(S)							
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
327		51		327	52	55	57				
INTERNATIONAL CLASSIFICATION											
H	0	3	F								
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HIEP NGUYEN 02.04.06 (Assistant Examiner) (Date)		 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)		Total Claims Allowed: 22	
(Legal Instruments Examiner) (Date)		2/4/06 (Date)		O.G. Print Claim(s) 1	O.G. Print Fig. 2B

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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